SDFS048A - D2932, MARCH 1987 - REVISED OCTOBER 1993

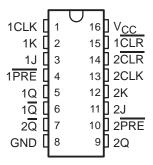
 Package Options Include Plastic Small-Outline Packages and Standard Plastic 300-mil DIPs

description

The SN74F112 contains two independent J-K negative-edge-triggered flip-flops. A low level at the preset (PRE) or clear (CLR) inputs sets or resets the outputs regardless of the levels of the other inputs. When PRE and CLR are inactive (high), data at the J and K inputs meeting the setup time requirements is transferred to the outputs on the negative-going edge of the clock pulse. Clock triggering occurs at a voltage level and is not directly related to the rise time of the clock pulse. Following the hold-time interval, data at the J and K inputs may be changed without affecting the levels at the outputs. The SN74F112 can perform as a toggle flip-flop by tying J and K high.

The SN74F112 is characterized for operation from 0°C to 70°C.

D OR N PACKAGE (TOP VIEW)



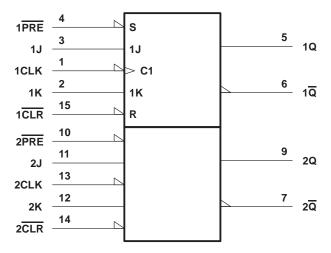
FUNCTION TABLE

INPUTS					OUTPUTS		
PRE	CLR	CLK	J	K	Q	Q	
L	Н	Х	Χ	Х	Н	L	
Н	L	X	Χ	X	L	Н	
L	L	X	Χ	X	H [†]	H [†]	
Н	Н	\downarrow	L	L	Q_0	\overline{Q}_0	
Н	Н	\downarrow	Н	L	Н	L	
Н	Н	\downarrow	L	Н	L	Н	
Н	Н	\downarrow	Н	Н	Toggle		
Н	Н	Н	Χ	Χ	Q ₀	\overline{Q}_0	

[†] The output levels in this configuration are not guaranteed to meet the minimum levels for V_{OH}. Furthermore, this configuration is nonstable; that is, it will not persist when either PRE or CLR returns to its inactive (high) level.

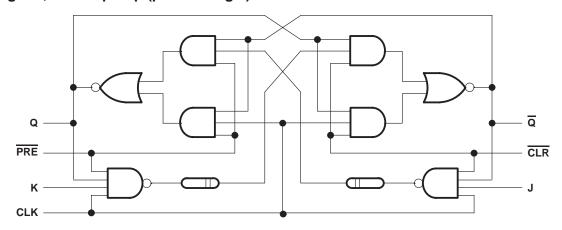
SDFS048A - D2932, MARCH 1987 - REVISED OCTOBER 1993

logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram, each flip-flop (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V _{CC}	0.5 V to 7 V
Input voltage range, V _I (see Note 1)	1.2 V to 7 V
Input current range	-30 mA to 5 mA
Voltage range applied to any output in the high state	0.5 V to V _{CC}
Current into any output in the low state	40 mA
Operating free-air temperature range	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input voltage ratings may be exceeded provided the input current ratings are observed.



SDFS048A - D2932, MARCH 1987 - REVISED OCTOBER 1993

recommended operating conditions

		MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
VIL	Low-level input voltage			0.8	V
lik	Input clamp current			-18	mA
ІОН	High-level output current			- 1	mA
lOL	Low-level output current			20	mA
TA	Operating free-air temperature	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TE	TEST CONDITIONS			MAX	UNIT	
VIK		$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2	V	
V		$V_{CC} = 4.5 \text{ V},$	I _{OH} = – 1 mA	2.5	3.4		V	
VOH		$V_{CC} = 4.75 \text{ V},$	$I_{OH} = -1 \text{ mA}$	2.7			V	
VOL		V _{CC} = 4.5 V,	$I_{OL} = 20 \text{ mA}$		0.3	0.5	V	
II		V _{CC} = 5.5 V,	V _I = 7 V			0.1	mA	
IIH		V _{CC} = 5.5 V,	V _I = 2.7 V			20	μΑ	
	J or K					- 0.6		
I _I L	PRE or CLR	V _{CC} = 5.5 V,	$V_{I} = 0.5 V$			-3	mA	
	CLK					- 2.4		
los‡		V _{CC} = 5.5 V,	V _O = 0	-60		-150	mA	
ICC	•	V _{CC} = 5.5 V,	See Note 2		12	19	mA	

[†] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

NOTE 2: ICC is measured with all outputs open, the Q and \overline{Q} outputs alternately high and the clock input grounded at the time of measurement.

timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

				V _{CC} = 5 V, T _A = 25°C		MAX	UNIT	
			MIN	MAX				
fclock	Clock frequency		0	110	0	100	MHz	
	Pulse duration	CLK high or low	4.5		5		ns	
t _W	ruise duration	CLR or PRE low	4.5		5		115	
	Saturations data before CLK	High	4		5		ns	
t _{su}	Setup time, data before CLK↓	Low	3		3.5			
th	Hold time data after CLK	High	0		0			
	Hold time, data after CLK↓	Low	0		0		ns	
t _{su}	Setup time, inactive state, data before CLK↓§	CLR or PRE high	4	·	5	·	ns	

[§] Inactive-state state setup time is also referred to as recovery time.

[‡] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

SN74F112 DUAL NEGATIVE-EDGE-TRIGGERED J-K FLIP-FLOP WITH CLEAR AND PRESET

SDFS048A - D2932, MARCH 1987 - REVISED OCTOBER 1993

switching characteristics (see Note 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V_{CC} = 5 V, C_{L} = 50 pF, R_{L} = 500 Ω, T_{A} = 25°C			V_{CC} = 4.5 V to 5.5 V, C_L = 50 pF, R_L = 500 Ω , T_A = MIN to MAX †		UNIT
			MIN	TYP	MAX	MIN	MAX	
f _{max}			110	130		100		MHz
^t PLH	CLK	0 0	1.2	4.6	6.5	1.2	7.5	ns
^t PHL		Q or Q	1.2	4.6	6.5	1.2	7.5	115
t _{PLH}	PRE or CLR	Q or $\overline{\mathbb{Q}}$	1.2	4.1	6.5	1.2	7.5	ns
^t PHL	TINE OF CER		1.2	4.1	6.5	1.2	7.5	

[†] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 3: Load circuits and waveforms are shown in Section 1.



IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated

Copyright © Each Manufacturing Company.

All Datasheets cannot be modified without permission.

This datasheet has been download from:

www.AllDataSheet.com

100% Free DataSheet Search Site.

Free Download.

No Register.

Fast Search System.

www.AllDataSheet.com